

### IEEE SW Test Workshop

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# A Probe Data Collection System Test Head Cummap (THC)



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### Background

- HVM wafer test
- Probe damage observations



- Infrequent, but catastrophic
- Root cause incident
- Large wafer defects
- Silent killers
- Need a data collection system
- TestHeadCummap (THC)



## **THC Objectives**

- Document the probe damage
- Analyze information
- Trends, Paretos, Cummaps
- Drive solutions



#### **THC Methods**

- Excel<sup>©</sup> spreadsheets
- Macro for simple data entry
- SAS JMP<sup>©</sup> script
- Database created
- Graphs: Trend, pareto, and cummap







#### Results

- THC output revealed systematic regions for probe burning
- THC trends provided evidence of turn-on and turn-off
- THC Paretos showed specific power planes for further scrutiny
- THC graphs compared cross factory and cross products



## Summary

- Consolidate probe damage information
- Cumulate across fleet of probe cards
- Use statistical methods to find outliers
- Drive solutions to reduce probe energy
- Save \$\$\$ in probe card costs



## **Next Steps**

- Some weaknesses of THC:
  - Hundreds of Excel files
  - Fragmented database
  - Inadvertent spreadsheet changes
- A new tool is in development today
  - Uses a web-based interface for technicians
  - Stores probe damage in SQL database



### Acknowledgements

- The following Intel employees were crucial to the success of the THC program:
  - Robert Miller: F11x
  - Jesus Martinez Ponce: AFO
  - Peter Truong: D1C







谢谢你





# THANK YOU

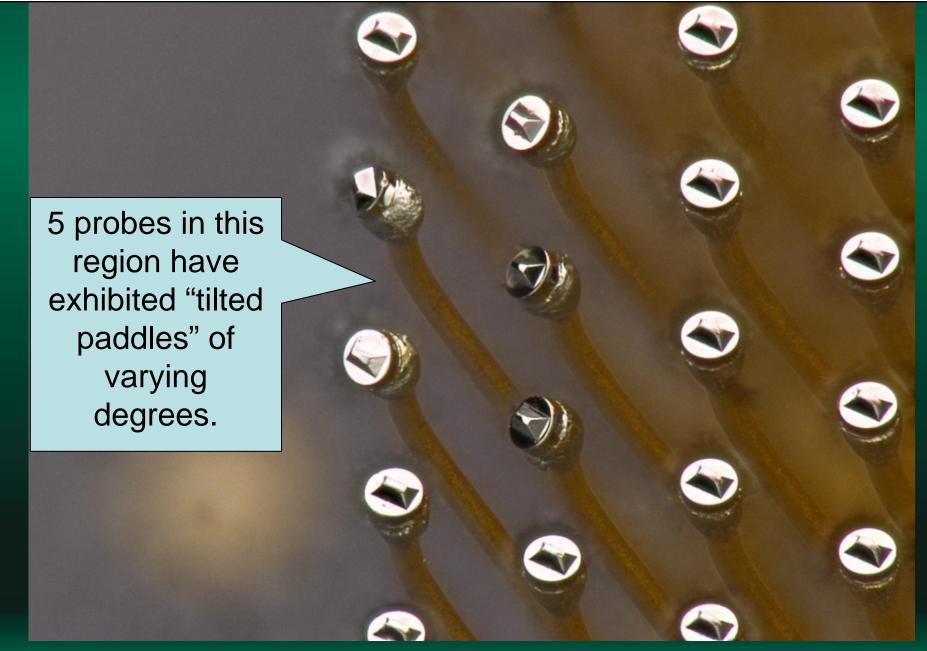
















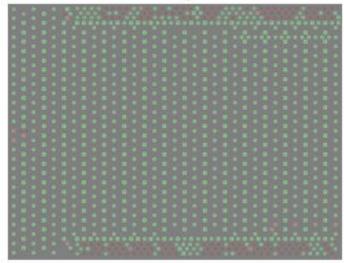
#### Visuals are performed



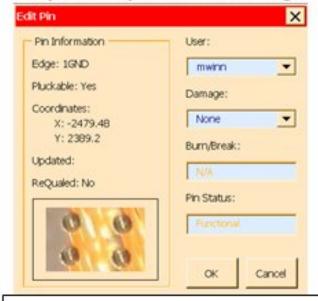
#### Open the padmap file

■ WDAFxxA054.XLS
■ WDAFxxA108.XLS
■ WDAFxxA109.XLS
■ WDAFxxA150.XLS

#### Find the probe



#### Update probe damage



Save the padmap file



